



CMOS 12-Bit Buffered Multiplying DAC

General Description

The MX7545 is a 12-bit CMOS multiplying digital-to-analog converter (DAC) with internal data latches. Input data is loaded as a single 12-bit word and latched under the control of CS and WR inputs. When CS and WR are low, the input data latches are transparent and the DAC output responds to any changes in the digital input.

MX7545 works with a single +5V or +15V power supply. Electrical characteristics are specified at both of these supply voltages. With a +5V supply, the digital inputs are +5V TTL and CMOS compatible while high voltage CMOS compatibility is maintained at +15V supply range.

Maxim MX7545 uses low tempco thin-film resistors which are laser-trimmed to result in linearity errors that are typically $\pm 1/4$ LSB and gain errors of maximum ± 1 LSB (G grade).

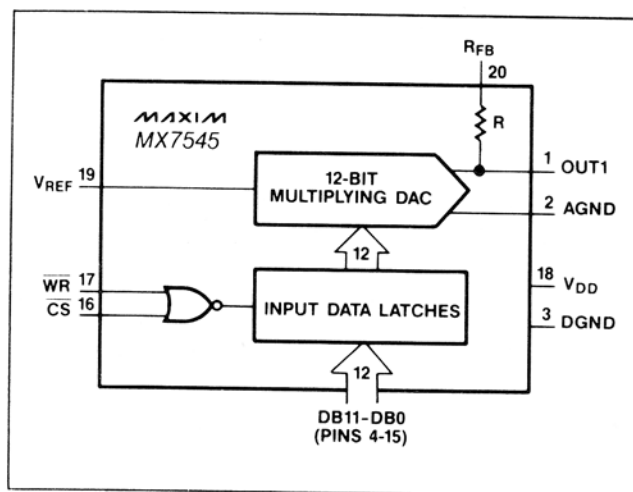
The digital inputs are designed with improved protection against electrostatic discharge (ESD) damage and can typically withstand to over 6,000V of ESD voltages.

The MX7545 is supplied in 20-lead narrow DIP and Small Outline packages.

Applications

- Motion Control Systems
- Automatic Test Equipment
- μ P Controlled Calibration Circuitry
- Programmable Gain Amplifiers
- Programmable Power Supplies

Functional Diagram



Features

- ◆ 12-Bit Resolution
- ◆ ± 1 LSB Gain Accuracy (G Grade)
- ◆ Single Supply Operation
- ◆ Improved ESD Protection
- ◆ CMOS/TTL Compatible for $V_{DD} = +5V$
- ◆ CMOS Compatible for $V_{DD} = +15V$

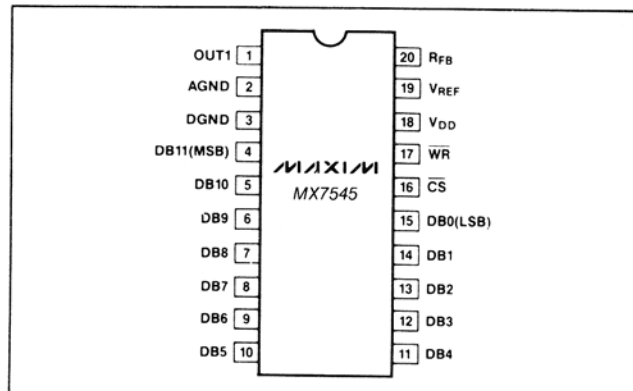
Ordering Information

PART	TEMP. RANGE	PACKAGE*	ERROR
MX7545JN	0°C to +70°C	Plastic DIP	± 2 LSB
MX7545KN	0°C to +70°C	Plastic DIP	± 1 LSB
MX7545LN	0°C to +70°C	Plastic DIP	$\pm 1/2$ LSB
MX7545GLN	0°C to +70°C	Plastic DIP	$\pm 1/2$ LSB
MX7545JCWP	0°C to +70°C	Small Outline	± 2 LSB
MX7545KCWP	0°C to +70°C	Small Outline	± 1 LSB
MX7545LCWP	0°C to +70°C	Small Outline	$\pm 1/2$ LSB
MX7545GLCWP	0°C to +70°C	Small Outline	$\pm 1/2$ LSB
MX7545J/D	0°C to +70°C	Dice	± 2 LSB
MX7545AQ	-25°C to +85°C	CERDIP**	± 2 LSB
MX7545BQ	-25°C to +85°C	CERDIP**	± 1 LSB
MX7545CQ	-25°C to +85°C	CERDIP**	$\pm 1/2$ LSB
MX7545GCQ	-25°C to +85°C	CERDIP**	$\pm 1/2$ LSB
MX7545SD	-55°C to +125°C	Ceramic	± 2 LSB
MX7545TD	-55°C to +125°C	Ceramic	± 1 LSB
MX7545UD	-55°C to +125°C	Ceramic	$\pm 1/2$ LSB
MX7545GUD	-55°C to +125°C	Ceramic	$\pm 1/2$ LSB
MX7545SQ	-55°C to +125°C	CERDIP**	± 2 LSB
MX7545TQ	-55°C to +125°C	CERDIP**	± 1 LSB
MX7545UQ	-55°C to +125°C	CERDIP**	$\pm 1/2$ LSB
MX7545GUQ	-55°C to +125°C	CERDIP**	$\pm 1/2$ LSB

* All devices—20 lead packages

**Maxim reserves the right to ship Ceramic packages in lieu of CERDIP packages.

Pin Configuration



Maxim Integrated Products 1

For pricing, delivery, and ordering information, please contact Maxim/Dallas Direct! at 1-888-629-4642, or visit Maxim's website at www.maxim-ic.com.

MX7545

CMOS 12-Bit Buffered Multiplying DAC

ABSOLUTE MAXIMUM RATINGS ($T_A = +25^\circ\text{C}$ unless otherwise stated.)

V_{DD} to DGND	-0.3 to +17V
Digital Input Voltage to DGND	-0.3 to V_{DD}
V_{RFB} , V_{REF} to DGND	$\pm 25\text{V}$
V_{OUT1} to DGND	-0.3 to V_{DD}
AGND to DGND	-0.3 to V_{DD}
Power dissipation to $+75^\circ\text{C}$ (any package)	450mW
Derate above 75°C by	6mW/ $^\circ\text{C}$

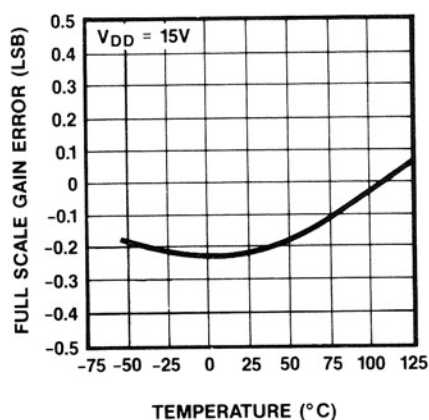
Operating Temperature Ranges

J, K, L, GL	0°C to $+70^\circ\text{C}$
A, B, C, GC	-25°C to $+85^\circ\text{C}$
S, T, U, GU	-55°C to $+125^\circ\text{C}$
Storage Temperature	-65°C to $+150^\circ\text{C}$
Lead Temperature (Soldering 10 seconds)	$+300^\circ\text{C}$

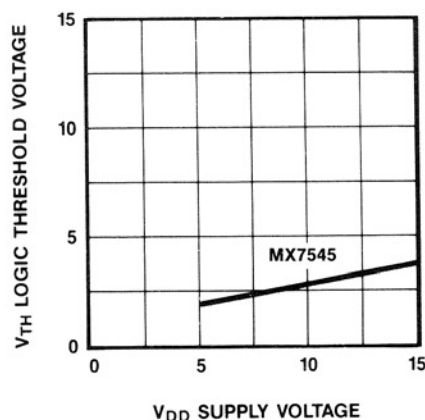
Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions above those indicated in the operational sections of the specification is not implied. Exposure to absolute Maximum ratings conditions for extended periods may affect the device reliability.

Typical Operating Characteristics

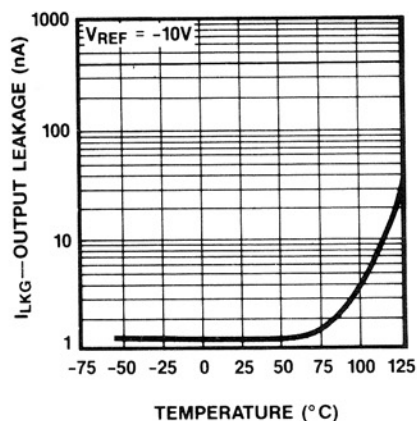
**FULL-SCALE GAIN ERROR
vs TEMPERATURE**



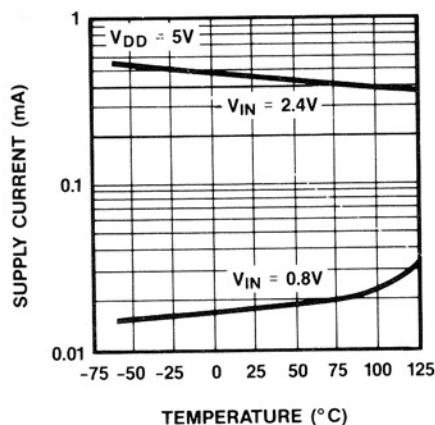
**LOGIC THRESHOLD VOLTAGE
vs SUPPLY VOLTAGE**



**OUTPUT LEAKAGE CURRENT
vs TEMPERATURE**



**SUPPLY CURRENT
vs TEMPERATURE**



CMOS 12-Bit Buffered Multiplying DAC

ELECTRICAL CHARACTERISTICS

($V_{DD} = +5V$, $V_{REF} = +10V$, $V_{OUT1} = 0V$, AGND = DGND. Over specified temperature range unless otherwise specified.)

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS
STATIC PERFORMANCE							
Resolution	N					12	Bits
Relative Accuracy	INL		J,A,S K,B,T L,C,U GL,GC,GU			±2 ±1 ±1/2 ±1/2	LSB LSB LSB LSB
Differential Non-Linearity	DNL	10-bit Monotonic 12-bit Monotonic 12-bit Monotonic 12-bit Monotonic	J,A,S K,B,T L,C,U GL,GC,GU			±4 ±1 ±1 ±1	LSB LSB LSB LSB
Gain Error (Note 1)	FSE		J,A,S K,B,T			±20 ±10	LSB LSB
			L,C,U T _A = +25°C Over Temp.			±5 ±6	LSB LSB
			GL,GC,GU T _A = +25°C Over Temp.			±1 ±2	LSB LSB
Gain Tempco ΔGain/ΔTemp. (Note 2)	TCFS				±2	±5	ppm/°C
DC Supply Rejection ΔGain/ΔV _{DD} (Note 2)	PSR	ΔV _{DD} = ±5%	T _A = +25°C Over Temp.			0.015 0.03	%/% %/%
DYNAMIC PERFORMANCE							
Current Settling Time (Note 2)	t _s	To ±1/2 LSB. OUT1 Load is 100ohms. CS = 0V. DAC output measured from falling edge of WR.				2	μs
Propagation Delay (Note 2)	t _{PD}	From digital inputs, DB11-DB0, change from V _{DD} to 0V or 0V to V _{DD} , to 90% of final analog output. OUT1 load is: R = 100ohms/C = 13pF.		T _A = +25°C		300	ns
Digital to Analog Glitch Impulse	Q	V _{REF} = AGND		T _A = +25°C		400	nV-s
AC Feedthrough at OUT1 (Note 3)	FTE	V _{REF} = ±10V, 10kHz sinewave, DB11-DB0 = 0V.			5		mVp-p
REFERENCE INPUT							
Input Resistance	R _{REF}	V _{REF} pin to AGND		7	11	25	kohms
Input Resistance Tempco	TCR				-300		ppm/°C

Note 1: Using internal feedback resistor, RFB. DAC register loaded with 1111 1111 1111. Gain error is adjustable using the circuits of Figures 3, 4 and 8.

Note 2: Guaranteed by design but not tested.

Note 3: In ceramic packages the feedthrough can be further reduced by grounding the metal lid of the package.

Note 4: Sample tested at $25^\circ C$ to ensure compliance.

Note 5: See timing diagram for definitions of the switching times.

CMOS 12-Bit Buffered Multiplying DAC

ELECTRICAL CHARACTERISTICS (Continued)

($V_{DD} = +5V$, $V_{REF} = +10V$, $V_{OUT1} = 0V$, AGND = DGND. Over specified temperature range unless otherwise specified.)

PARAMETER	SYMBOL	CONDItIONS		MIN	TYP	MAX	UNITS
ANALOG OUTPUTS							
OUT1 Capacitance (Note 2)	C _{OUT1}	DB11-DB0 = 0V, $\overline{WR}$ = $\overline{CS}$ = 0V DB11-DB0 = V _{DD} , $\overline{WR}$ = $\overline{CS}$ = 0V				70 200	pF pF
OUT1 Leakage Current	I _{LKG}	$\overline{WR}$ = $\overline{CS}$ = 0V DB11-DB0 = 0V	J,K,L,GL T _A = +25°C Over Temp.			10 50	nA nA
			A,B,C,GC T _A = +25°C Over Temp.			10 50	nA nA
			S,T,U,GU T _A = +25°C Over Temp.			10 200	nA nA
DIGITAL INPUTS							
Input High Voltage	V _{IH}			2.4			V
Input Low Voltage	V _{IL}					0.8	V
Input Current	I _{IN}	V _{IN} = 0V or V _{DD}	T _A = +25°C Over Temp.		±0.001	±1 ±10	μA μA
Input Capacitance (Note 2)	C _{IN}	V _{IN} = 0V; DB11-DB0 V _{IN} = 0V; $\overline{WR}$, $\overline{CS}$				5 20	pF pF
SWITCHING CHARACTERISTICS (Notes 4, 5)							
Chip Select to Write Setup Time	t _{CS}	T _A = +25°C Over Temp.		280 380	200 270		ns ns
Chip Select to Write Hold Time	t _{CH}			0			ns
Write Pulse Width	t _{WR}	t _{CS} ≥ t _{WR} , t _{CH} ≥ 0	T _A = +25°C Over Temp.	250 400	175 280		ns ns
Data Setup Time	t _{DS}	T _A = +25°C Over Temp.		140 210	100 150		ns ns
Data Hold Time	t _{DH}			10			ns
POWER SUPPLY							
Supply Current	I _{DD}	All digital inputs: V _{IL} or V _{IH} : 0V or V _{DD} , T _A = +25°C : 0V or V _{DD} Over Temp.			10 10	2 100 500	mA μA μA

Note 1: Using internal feedback resistor, RFB. DAC register loaded with 1111 1111 1111. Gain error is adjustable using the circuits of Figures 3, 4 and 8.

Note 2: Guaranteed by design but not tested.

Note 3: In ceramic packages the feedthrough can be further reduced by grounding the metal lid of the package.

Note 4: Sample tested at $25^\circ C$ to ensure compliance.

Note 5: See timing diagram for definitions of the switching times.

CMOS 12-Bit Buffered Multiplying DAC

MX7545

ELECTRICAL CHARACTERISTICS

($V_{DD} = +15V$, $V_{REF} = +10V$, $V_{OUT1} = 0V$, AGND = DGND. Over specified temperature range unless otherwise specified.)

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS
STATIC PERFORMANCE							
Resolution	N					12	Bits
Relative Accuracy	INL		J,A,S K,B,T L,C,U GL,GC,GU			±2 ±1 ±1/2 ±1/2	LSB LSB LSB LSB
Differential Non-Linearity	DNL	10-bit Monotonic 12-bit Monotonic 12-bit Monotonic 12-bit Monotonic	J,A,S K,B,T L,C,U GL,GC,GU			±4 ±1 ±1 ±1	LSB LSB LSB LSB
Gain Error (Note 1)	FSE		J,A,S K,B,T L,C,U GL,GC,GU T _A = +25°C Over Temp.			±25 ±15 ±10 ±6 ±7	LSB LSB LSB LSB LSB
Gain Tempco ΔGain/ΔTemp. (Note 2)	TCFS				±2	±10	ppm/°C
DC Supply Rejection ΔGain/ΔV _{DD} (Note 2)	PSR	ΔV _{DD} = ±5%	T _A = +25°C Over Temp.			0.01 0.02	%/% %/%
DYNAMIC PERFORMANCE							
Current Settling Time (Note 2)	t _S	To ±1/2 LSB OUT1 Load is 100ohms. CS = 0V. DAC output measured from falling edge of WR.				2	μs
Propagation Delay (Note 2)	t _{PD}	From digital inputs, DB11-DB0, change from V _{DD} to 0V or 0V to V _{DD} , to 90% of final analog output. OUT1 Load is: R = 100ohms/C = 13pF.				250	ns
Digital to Analog Glitch Impulse	Q	V _{REF} = AGND					

CMOS 12-Bit Buffered Multiplying DAC

ELECTRICAL CHARACTERISTICS (Continued)

($V_{DD} = +15V$, $V_{REF} = +10V$, $V_{OUT1} = 0V$, AGND = DGND. Over specified temperature range unless otherwise specified.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
DIGITAL INPUTS (Continued)						
Input Current	I_{IN}	$V_{IN} = 0V$ or V_{DD}		± 0.001	± 1 ± 10	μA μA
Input Capacitance (Note 2)	C_{IN}	$V_{IN} = 0V$; DB11-DB0 $V_{IN} = 0V$; WR, CS			5 20	pF pF
SWITCHING CHARACTERISTICS (Notes 4, 5)						
Chip Select to Write Setup Time	t_{CS}			$T_A = +25^\circ C$ Over Temp.	180 200	120 150 ns ns
Chip Select to Write Hold Time	t_{CH}		0			ns
Write Pulse Width	t_{WR}	$t_{CS} \geq t_{WR}$, $t_{CH} \geq 0$		$T_A = +25^\circ C$ Over Temp.	160 240	100 170 ns ns
Data Setup Time	t_{DS}			$T_A = +25^\circ C$ Over Temp.	90 120	60 80 ns ns
Data Hold Time	t_{DH}		10			ns
POWER SUPPLY						
Supply Current	I_{DD}	All digital inputs: V_{IL} or V_{IH} : $0V$ or V_{DD} , : $0V$ or V_{DD}		$T_A = +25^\circ C$ Over Temp.	10 10	2 100 500 mA μA μA

Note 1: Using internal feedback resistor, RFB. DAC register loaded with 1111 1111 1111. Gain error is adjustable using the circuits of Figures 3, 4 and 8.

Note 2: Guaranteed by design but not tested.

Note 3: In ceramic packages the feedthrough can be further reduced by grounding the metal lid of the package.

Note 4: Sample tested at $25^\circ C$ to ensure compliance.

Note 5: See timing diagram for definitions of the switching times.

Detailed Description

D/A Converter

The basic MX7545 DAC circuit consists of a laser trimmed, thin-film R-2R resistor array with NMOS current switches as shown in Figure 1. Binary weighted currents are switched to either OUT1 or AGND depending on the status of each output bit. Although the current at OUT1 and AGND will depend on the digital input code, the sum of the two output currents is always equal to the input current at V_{REF} .

Either current output can be converted into a voltage externally by adding an output amplifier (Figure 3). The V_{REF} input accepts a wide range of signals including fixed and time varying voltage or current inputs. If a current source is used for the reference input, then a low temperature coefficient external resistor should be used for R_{FB} to minimize gain variation with temperature.

The internal feedback resistor R_{FB} is compensated with an NMOS switch that matches the NMOS switches used in the R-2R array. This results in excellent supply rejection and gain temperature coefficient.

The I_{OUT1} pin output capacitance, C_{OUT1} , is code dependent and is typically 70pF to 200pF, with all switches to AGND and I_{OUT1} , respectively.

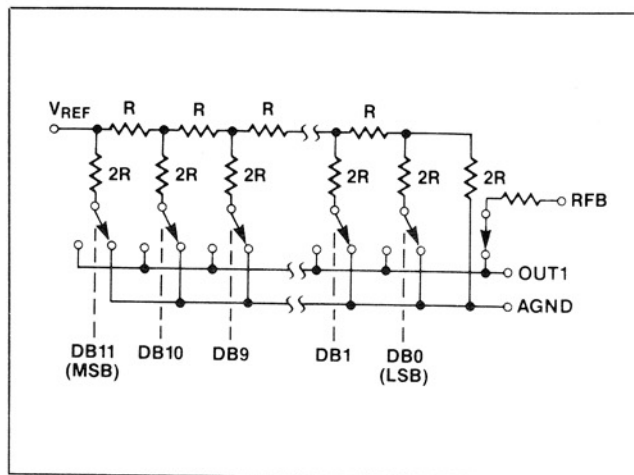


Figure 1. Simplified D/A Circuit of MX7545

Digital Circuit

The digital circuit for one bit is shown in Figure 2. The digital CONTROL signal is HIGH when WR and CS are both low. When WR and CS are tied low, the digital input directly controls the D/A switches.

CMOS 12-Bit Buffered Multiplying DAC

MX7545

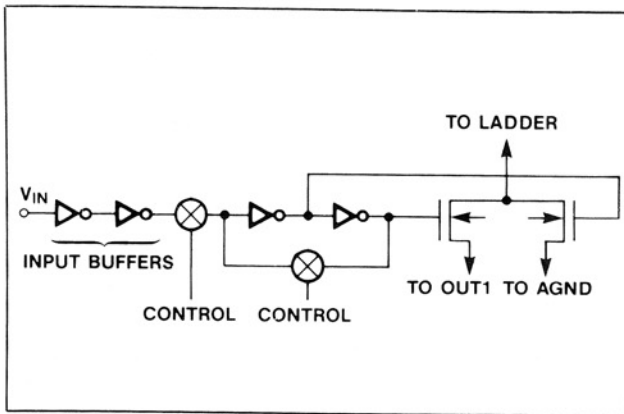
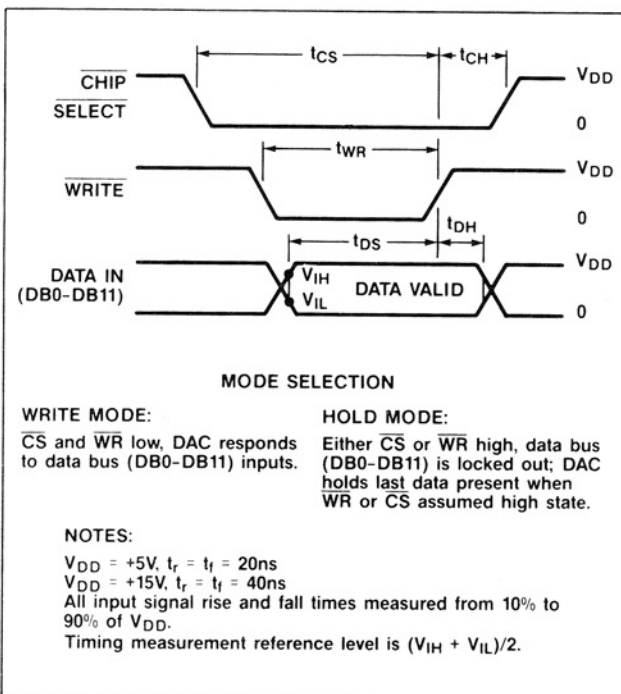


Figure 2. Digital Input Structure

The input buffer inverters act as a level shifter converting TTL levels into CMOS logic levels. These input buffers are CMOS/TTL compatible (0.8V and 2.4V) at $V_{DD} = +5V$. The MX7545 also works with $V_{DD} = +15V$ where the input buffers are CMOS compatible (1.5V and 13.5V) only. With the digital input voltages at 1V to 6V the input buffers work in their linear regions drawing current from the power supply. Therefore to minimize high supply currents the digital input voltages should be kept as close to the supply and ground voltages (V_{DD} and DGND) as possible.

All digital inputs are ruggedized against electrostatic-discharge (ESD) sensitivity and can typically withstand ESD voltages of over 6kV.



Circuit Configurations

Unipolar Operation

The most common configuration for the MX7545 is shown in Figure 3. This circuit is used for unipolar binary operation or two-quadrant multiplication. The

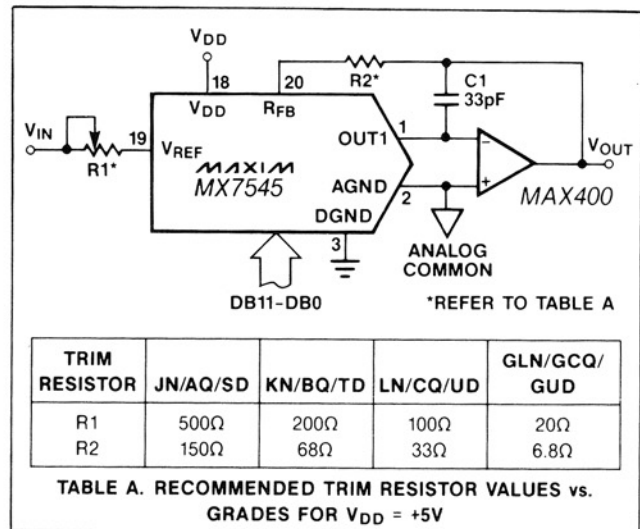


Figure 3. Unipolar Binary Operation

Table 1. Unipolar Binary Code Table for Circuit of Figure 3

DIGITAL INPUT		ANALOG OUTPUT
MSB	LSB	
1 1 1 1	1 1 1 1	$-V_{IN} \left(\frac{4095}{4096} \right)$
1 0 0 0	0 0 0 0	$-V_{IN} \left(\frac{2048}{4096} \right) = -1/2 V_{IN}$
0 0 0 0	0 0 0 1	$-V_{IN} \left(\frac{1}{4096} \right)$
0 0 0 0	0 0 0 0	0

code table for this mode is given in Table 1. Note that the polarity of the output is the inverse of the reference voltage, V_{REF} .

In many applications the gain adjustment will not be necessary, especially when using the "G" suffix parts with guaranteed maximum ± 1 LSB gain errors. In those cases and also when the gain is trimmed at the reference source, resistors R1 and R2 in Figure 3 can be omitted. However, if the trims are desired and the DAC is operated over a wide temperature range, then low tempco ($<300ppm/^{\circ}C$) resistors should be used for R1 and R2.

CMOS 12-Bit Buffered Multiplying DAC

The capacitor C1 provides phase compensation and helps reduce the overshoot and ringing when using fast amplifiers at the output of the DACs.

Bipolar Operation

With the circuit configuration shown in Figure 4, the MX7545 operates in the bipolar, or 4-quadrant multiplying mode. A second amplifier and three matched resistors, R3, R4 and R5 are required. These resistors must be of the same material (preferably metal film or wire-wound) for good temperature characteristics, and they should match to 0.01% for 12-bit performance.

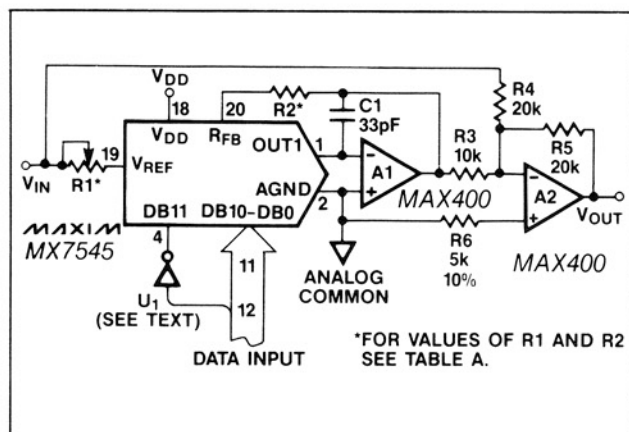


Figure 4. Bipolar Operation (2's Complement Code)

Table 2. 2's Complement Code Table for Circuit of Figure 4

DIGITAL INPUT		
MSB	LSB	ANALOG OUTPUT
0	1 1 1 1 1 1 1 1 1 1 1 1	$+V_{IN} \left(\frac{2047}{2048} \right)$
0	0 0 0 0 0 0 0 0 0 0 0 1	$+V_{IN} \left(\frac{1}{2048} \right)$
0	0 0 0 0 0 0 0 0 0 0 0 0	0
1	1 1 1 1 1 1 1 1 1 1 1 1	$-V_{IN} \left(\frac{1}{2048} \right)$
1	0 0 0 0 0 0 0 0 0 0 0 0	$-V_{IN} \left(\frac{2048}{2048} \right)$

The code table for the output, which is 2's complement is listed in Table 2. In multiplying applications, the MSB determines output polarity while the other 11 bits control amplitude. The U1 inverter on the MSB line converts the 2's complement input code to offset-binary code. If this inversion is done in software using an exclusive-OR instruction or the input code is in offset binary, the U1 inverter can be omitted. Table 3 shows the code relationships to output voltage for the offset binary operation.

To adjust the circuit with offset binary code, load the DAC with a code of 1000 0000 0000 and trim R1 for a 0V output. With R1 and R2 omitted, an alternative zero trim is to adjust the ratio of R3 and R4 for 0V out. Full scale can be trimmed by loading the DAC with all "zeros" or all "ones" and adjusting the amplitude of V_{REF} or varying R5 until the desired positive or negative output is obtained. In many applications the gain adjustment will not be necessary, especially when using the "G" suffix parts with guaranteed maximum ± 1 LSB gain errors. In those cases and also when the gain is trimmed at the reference source, resistors R1 and R2 in Figure 4 can be omitted. However, if the trims are desired and the DAC is operated over a wide temperature range, then low tempco ($<300\text{ppm}/^\circ\text{C}$) resistors should be used for R1 and R2.

(Voltage Mode) Single Supply

The MX7545 can be conveniently used in single supply (voltage mode) operation with OUT1 and AGND biased at any voltage between DGND and V_{DD} . This is possible since the ladder termination resistor is connected to AGND. OUT1 and AGND must not be allowed to go 0.3V lower or higher than the DGND or V_{DD} , respectively. Otherwise, internal diodes would turn on and a heavy current flow from the supply, possibly destroying the device.

Figure 5 shows the MX7545 connected as a voltage output DAC. OUT1 is connected to the reference input and AGND is grounded. V_{REF} pin, now the DAC output, is a voltage source with a constant impedance equal to the reference input resistance (typically 11kohms). This output should be buffered with an op-amp when a lower output impedance is required. R_{FB} pin is not used in this mode.

Table 3. Offset Binary Code Table

DIGITAL INPUT		
MSB	LSB	ANALOG OUTPUT
1	1 1 1 1 1 1 1 1 1 1 1 1	$+V_{REF} \left(\frac{2047}{2048} \right)$
1	0 0 0 0 0 0 0 0 0 0 0 1	$+V_{REF} \left(\frac{1}{2048} \right)$
1	0 0 0 0 0 0 0 0 0 0 0 0	0
0	1 1 1 1 1 1 1 1 1 1 1 1	$-V_{REF} \left(\frac{1}{2048} \right)$
0	0 0 0 0 0 0 0 0 0 0 0 0	$-V_{REF} \left(\frac{2048}{2048} \right)$

The input impedance of the reference input (OUT1) for this mode is code dependent, and the response time of the circuit depends on the behaviour of the reference source with changing load conditions.

Two advantages of the voltage mode operation are

CMOS 12-Bit Buffered Multiplying DAC

MX7545

single supply operation and that a negative reference is not required for a positive output. It should also be noted that the reference input (the voltage at OUT1) must always be positive and is limited to no more than 2.5V when V_{DD} is 15V. If the reference voltage is greater than 2.5V or V_{DD} is reduced, resistance mismatches in the DAC's internal NMOS switches result in degraded linearity and differential nonlinearity (DNL). Figures 6 and 7 show the typical dependence of DNL on supply voltage, V_{DD} , and the reference voltage, V_{REF} . If the DAC is offset from DGND by biasing OUT1 and AGND at a voltage above DGND, this will effect DNL and its effect will be the same as reducing V_{DD} by the amount of the offset.

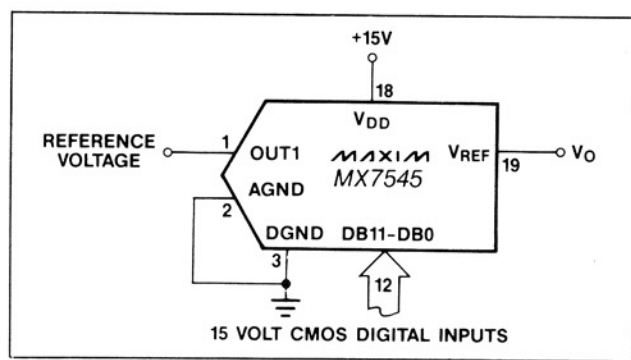


Figure 5. Single Supply Operating Using Voltage Switching Mode

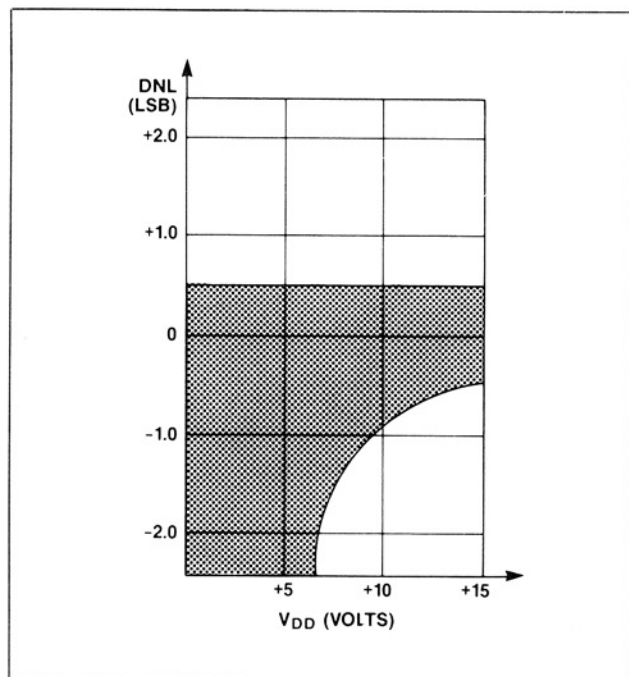


Figure 6. Differential Nonlinearity vs. V_{DD} for Figure 4 Circuit. Reference Voltage = 2.5 Volts. Shaded Area Shows Range of Values of Differential Nonlinearity that Typically Occur for L, C and U Grades.

The unipolar and bipolar circuits in Figures 3 and 4 can all be converted to voltage output mode. For example, Figure 8 shows the 2's complement bipolar circuit of Figure 4 modified to work with an output range of +2V to +8V around an offset ground potential of +5V from a single supply, V_{DD} , of +10V to 15V. The REF02 reference is used to bias the AGND at +5V. The R1 and R2 resistors form a voltage divider together

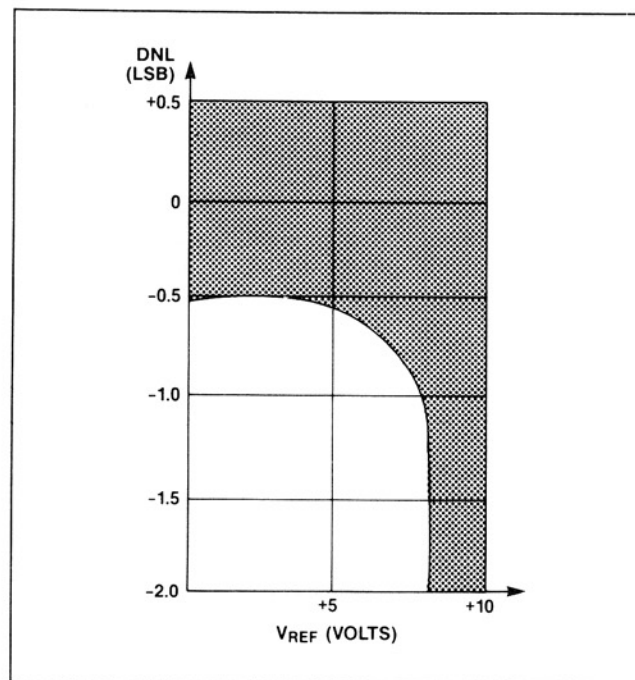


Figure 7. Differential Nonlinearity vs. Reference Voltage for Figure 4 Circuit. V_{DD} = 15 Volts. Shaded Area Shows Range of Values of Differential Nonlinearity that Typically Occur for L, C, and U Grades.

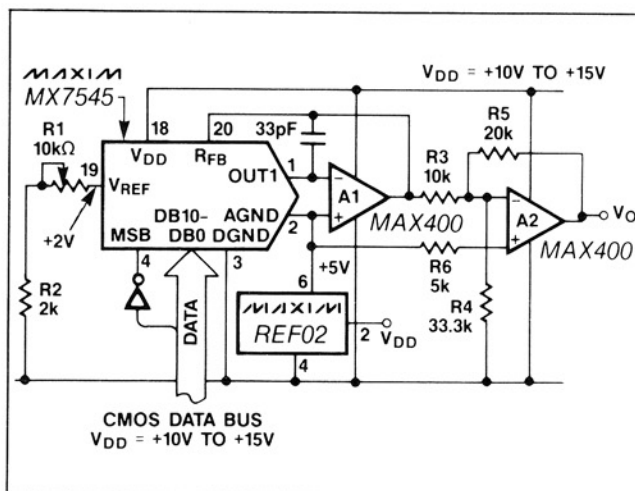


Figure 8. Single Supply "Bipolar" 2's Complement D/A Converter

CMOS 12-Bit Buffered Multiplying DAC

The DAC output follows the digital inputs when the WR and CS pins are low. In those systems where the data is not valid for the full period where WR is low, invalid outputs and voltage glitches can appear at the DAC output. Adjusting the timing of the WR signal so that it is low only when data is valid eliminates this problem.

Compensation

A compensation capacitor, C1, may be needed when the DAC is used with a high-speed output amplifier. The purpose of the capacitor is to cancel the pole formed by the DAC output capacitance C_{OUT1} and the internal feedback resistor, R_{FB} . Its value depends on the type of op-amp used but typically ranges from 10pF to 3pF. Too small a value causes output ringing while excess capacitance overdamps the output. The size of C1 can be minimized and the output voltage settling time improved by keeping the circuit board trace and stray capacitance at OUT1 as small as possible.

Grounding and Bypassing

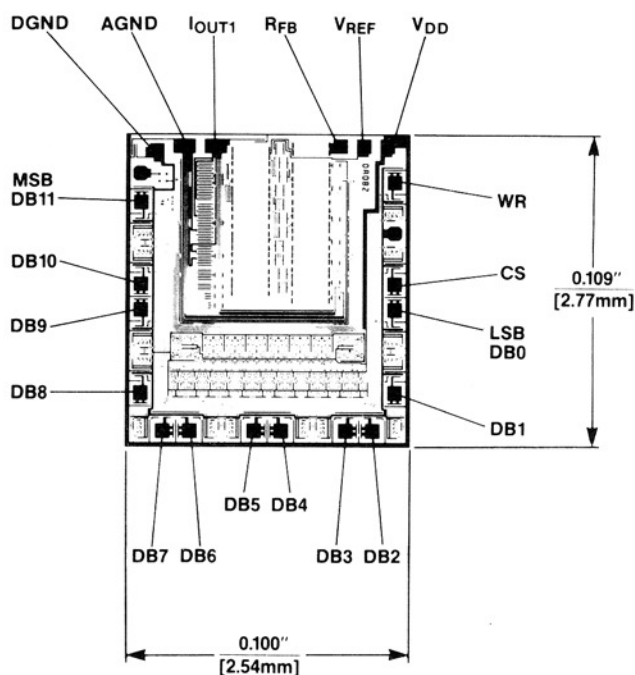
Since OUT1, AGND and noninverting input of the output amplifier are sensitive to offset voltages, nodes that are to be grounded should be connected directly to "single point" ground through a separate, low resistance (less than 0.2ohms) connection. The current at OUT1 and AGND varies with input code, creating a code dependent error if these terminals are connected to ground (or a "virtual ground") through a resistive path.

A 1 μ F bypass capacitor, in parallel with a 0.01 μ F ceramic capacitor, should be connected as close to the DAC V_{DD} and DGND pins as possible.

The MX7545 has high-impedance digital inputs. To minimize noise pick-up, they should be tied to either V_{DD} or DGND when not used. It is also a good practice to connect active inputs to V_{DD} or DGND through high valued resistors (1Mohms) to prevent static charge accumulation if these pins are left floating, such as when a circuit card is left unconnected.

It is also recommended that two back-to-back diodes be connected between the DGND and AGND pins in those systems where these pins tie on the backplane.

Chip Topology



MX7545

CMOS 12-Bit Buffered Multiplying DAC

Maxim cannot assume responsibility for use of any circuitry other than circuitry entirely embodied in a Maxim product. No circuit patent licenses are implied. Maxim reserves the right to change the circuitry and specifications without notice at any time.

12 _____ **Maxim Integrated Products, 120 San Gabriel Drive, Sunnyvale, CA 94086 (408) 737-7600**

© 1995 Maxim Integrated Products

Printed USA

MAXIM is a registered trademark of Maxim Integrated Products.



Компания «ЭлектроПласт» предлагает заключение долгосрочных отношений при поставках импортных электронных компонентов на взаимовыгодных условиях!

Наши преимущества:

- Оперативные поставки широкого спектра электронных компонентов отечественного и импортного производства напрямую от производителей и с крупнейших мировых складов;
- Поставка более 17-ти миллионов наименований электронных компонентов;
- Поставка сложных, дефицитных, либо снятых с производства позиций;
- Оперативные сроки поставки под заказ (от 5 рабочих дней);
- Экспресс доставка в любую точку России;
- Техническая поддержка проекта, помощь в подборе аналогов, поставка прототипов;
- Система менеджмента качества сертифицирована по Международному стандарту ISO 9001;
- Лицензия ФСБ на осуществление работ с использованием сведений, составляющих государственную тайну;
- Поставка специализированных компонентов (Xilinx, Altera, Analog Devices, Intersil, Interpoint, Microsemi, Aeroflex, Peregrine, Syfer, Eurofarad, Texas Instrument, Miteq, Cobham, E2V, MA-COM, Hittite, Mini-Circuits, General Dynamics и др.);

Помимо этого, одним из направлений компании «ЭлектроПласт» является направление «Источники питания». Мы предлагаем Вам помощь Конструкторского отдела:

- Подбор оптимального решения, техническое обоснование при выборе компонента;
- Подбор аналогов;
- Консультации по применению компонента;
- Поставка образцов и прототипов;
- Техническая поддержка проекта;
- Защита от снятия компонента с производства.



Как с нами связаться

Телефон: 8 (812) 309 58 32 (многоканальный)

Факс: 8 (812) 320-02-42

Электронная почта: org@eplast1.ru

Адрес: 198099, г. Санкт-Петербург, ул. Калинина, дом 2, корпус 4, литера А.